

September 2000 Revised February 2001

SSTV16857

14-Bit Register with SSTL-2 Compatible I/O and Reset

General Description

The SSTV16857 is a 14-bit register designed for use with 184 and 232 pin DDR-I memory modules. The device has a differential input clock, SSTL-2 compatible data inputs and a LVCMOS compatible RESET input. The device has been designed for compliance with the JEDEC DDR module and register specifications.

The device is fabricated on an advanced submicron CMOS process and is designed to operate at power supplies of less than 3.6V's.

Features

- Compliant with DDR-I registered module specifications
- Operates at 2.5V ± 0.2V V_{DD}
- SSTL-2 compatible input and output structure
- Differential SSTL-2 compatible clock inputs
- Low power mode when device is reset
- Industry standard 48 pin TSSOP package

Ordering Code:

Order Number	Package Number	Package Description				
SSTV16857MTD	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide				

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Pin Descriptions

Pin Name	Description
Q ₁ -Q ₁₄	SSTL-2 Compatible Output
D ₁ -D ₁₄	SSTL-2 Compatible Inputs
RESET	Asynchronous LVCMOS Reset Input
CK	Positive Master Clock Input
CK	Negative Master Clock Input
V _{REF}	Voltage Reference Pin for SSTL Level Inputs
V_{DDQ}	Power Supply Voltage for Output Signals
V_{DD}	Power Supply Voltage for Inputs

Truth Table

RESET	D _n	СК	СК	Q _n
L	X or Floating	X or Floating	X or Floating	7-70
Н	L	1	\downarrow	457
Н	Н	1	1	Н
H	X	L	Н	Q _n
- Н (X	Н	L	Q _n

- L = Logic LOW
- H = Logic HIGH
- X = Don't Care, but not floating unless noted
- ↑ = LOW-to-HIGH Clock Transition
- ↓ = HIGH-to-LOW Clock Transition

Functional Description

The SSTV16857 is a 14-bit register with SSTL-2 compatible inputs and outputs. Input data is captured by the register on the positive edge crossing of the differential clock pair.

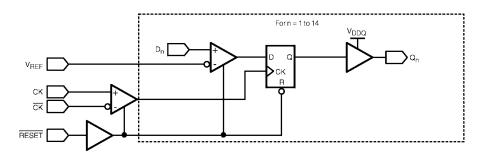
When the LV-CMOS RESET signal is asserted LOW, all outputs and internal registers are asynchronously placed into the LOW logic state. In addition, the clock and data differential comparators are disabled for power savings. Output glitches are prevented by disabling the internal registers more quickly than the input comparators. When

RESET is removed, the system designer must insure the clock and data inputs to the device are stable during the rising transition of the RESET signal.

The SSTL-2 data inputs transition based on the value of V_{REF} . V_{REF} is a stable system reference used for setting the trip point of the input buffers of the SSTV16857 and other SSTL-2 compatible devices.

The $\overline{\rm RESET}$ signal is a standard CMOS compatible input and is not referenced to the $\rm V_{REF}$ signal.

Logic Diagram



Absolute Maximum Ratings(Note 1)

-0.5V to +3.6V Supply Voltage ($V_{\rm DDQ}$) Supply Voltage (V_{DD}) -0.5V to +3.6V-0.5V to +3.6V Reference Voltage (V_{REF}) Input Voltage (V_I) -0.5V to $V_{DD} + 0.5V$

Output Voltage (VO)

 $-0.5 \mbox{V}$ to $\mbox{V}_{\mbox{DDQ}} + 0.5 \mbox{V}$ Outputs Active (Note 2)

DC Input Diode Current (I_{IK})

 $V_I < 0V$ $V_I > V_{DD}$ +50 mA DC Output Diode Current (I_{OK}) -50 mA $V_{O} < 0V$

 $V_O > V_{DD}$ +50 mA

DC Output Source/Sink Current

 (I_{OH}/I_{OL}) ±50 mA

DC V_{DD} or Ground Current

per Supply Pin (I_{DD} or Ground) ±100 mA Storage Temperature Range (T_{stg}) $-65^{\circ}C$ to $+150^{\circ}C$

Recommended Operating Conditions (Note 3)

Power Supply (V_{DDQ}) 2.3V to 2.7V

Power Supply (V_{DD})

Operating Range V_{DDQ} to 2.7V

Reference Supply

1.15 to 1.35 $(V_{REF} = V_{DDQ}/2)$

 $V_{REF} \pm 40 \; mV$ Termination Voltage (V_{TT}) Input Voltage 0V to V_{DD}

Output Voltage (VO)

-50 mA

0V to $V_{\rm DDQ}$ Output in Active States

Output Current I_{OH}/I_{OL}

 $V_{DD} = 2.3V$ to 2.7V±20 mA 0°C to +70°C

Free Air Operating Temperature (T_A)

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the "Electrical Characteristics" table are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: IO Absolute Maximum Rating must be observed.

Note 3: The $\overline{\text{RESET}}$ input of the device must be held at V_{DD} or GND to ensure $\underline{\text{proper}}$ device operation. The differential inputs must not be floating, unless $\overline{\text{RESET}}$ is asserted LOW.

DC Electrical Characteristics (2.3 $V \le V_{DD} \le 2.7V$)

Symbol	Parameter	Conditions	V _{DD}	Min	Max	Units	
Cymbol	r arameter	(V)			IWIAX	Onito	
V_{IKL}	Input LOW Clamp Voltage	I _I = -18 mA	2.3		-1.2	V	
V _{IKH}	Input HIGH Clamp Voltage	I _I = +18 mA	2.3		3.5	V	
V _{IH-AC}	AC HIGH Level Input Voltage	Data Inputs		V _{REF} +310mV		V	
V _{IL-AC}	AC LOW Level Input Voltage	Data Inputs			V _{REF} -310mV	V	
V _{IH-DC}	DC HIGH Level Input Voltage	Data Inputs		V _{REF} +150mV		V	
V _{IL-DC}	DC LOW Level Input Voltage	Data Inputs			V _{REF} -150mV	V	
V _{IH}	HIGH Level Input Voltage	RESET		1.7		V	
V _{IL}	LOW Level Input Voltage	RESET			0.7	V	
V _{ICR}	Common Mode Input Voltage Range	CLK, CLK		0.97	1.53	V	
V _{I(PP)}	Peak to Peak Input Voltage	CLK, CLK		360		mV	
V _{OH}	HIGH Level Output Voltage	$I_{OH} = -100 \mu A$	2.3 to 2.7	V _{DD} - 0.2		V	
		$I_{OH} = -16 \text{ mA}$	2.3	1.95		V	
V _{OL}	LOW Level Output Voltage	$I_{OL} = 100 \mu A$	2.3 to 2.7		0.2	V	
		I _{OL} = 16 mA	2.3		0.35	V	
I _I	Input Leakage Current $V_I = V_{DD}$ or GND		2.7		±5.0	μΑ	
I _{DD}	Static Standby	$\overline{RESET} = GND, I_{O} = 0$			10	μΑ	
	Static Operating	$\overline{RESET} = V_{DD}, I_{O} = 0$	2.7				
		$V_I = V_{IH(AC)}$ or $V_{IL(AC)}$			25	mA	
I _{DDD}	Dynamic Operating Current	$\overline{RESET} = V_DD, \; I_O = 0$					
	Clock Only	$V_I = V_{IH(AC)}$ or $V_{IL(AC)}$			90	μA/MHz	
		CK, CK Duty Cycle 50%					
	Dynamic Operating Current	$\overline{\text{RESET}} = V_{DD}, I_{O} = 0$	2.7				
	per Data Input	$V_I = V_{IH(AC)}$ or $V_{IL(AC)}$	2.7				
		CK, CK Duty Cycle 50%			15	μΑ/MHz	
		Data Input = 1/2 Clock					
		Rate 50% Duty Cycle					

DC Electrical Characteristics (Continued)

Symbol	Parameter	Conditions	V _{DD} (V)	Min	Max	Units
R _{OH}	Output HIGH On Resistance	$I_{OH} = -20 \text{ mA}$	2.3 to 2.7	7	20	Ω
R _{OL}	Output LOW On Resistance	I _{OL} = 20 mA	2.3 to 2.7	7	20	Ω
R _{O∆}	R _{OH} - R _{OL}	$I_{O} = 20 \text{ mA}, T_{A} = 25^{\circ}\text{C}$	2.5		4	Ω

AC Electrical Characteristics (Note 4)

		$T_A = 0$ °C to +70°C, 0	Units	
Symbol	Parameter	$\mathbf{V_{DD}} = \mathbf{2.5V} \pm \mathbf{0.2V};$		
		Min	Max	
f _{MAX}	Maximum Clock Frequency	200		MHz
t _W	Pulse Duration, CK, CK HIGH or LOW (Figure 2)	2.5		ns
t _{ACT} (Note 5)	Differential Inputs Activation Time, data inputs must be LOW after RESET HIGH (Figure 3)	22		ns
t _{INACT} (Note 5)	Differential Inputs De-activation Time, data and clock inputs must be held at valid levels (not floating) after RESET LOW	22		ns
t _S	Setup Time, Fast Slew Rate (Note 6)(Note 7) (Figure 5) Setup Time, Slow Slew Rate (Note 7)(Note 8) (Figure 5)	0.75 0.9		ns
t _H	Hold Time, Fast Slew Rate (Note 6)(Note 8) (Figure 5) Hold Time, Slow Slew Rate (Note 7)(Note 8) (Figure 5)	0.75		ns
t _{REM}	Reset Removal Time (Figure 7)	10		ns
t _{PHL} , t _{PLH}	Propagation Delay CLK, CLK to Q _n (Figure 4)	1.1	2.8	ns
t _{PHL}	Propagation Delay RESET to Q _n (Figure 6)		5.0	ns
t _{SK(Pn-Pn)}	Output to Output Skew		200	ps

Note 4: Refer to Figure 1 through Figure 7.

Note 5: This parameter is not production tested.

Note 6: For data signal input slew rate \geq 1 V/ns.

Note 7: For data signal input slew rate ≥ 0.5 V/ns and < 1 V/ns.

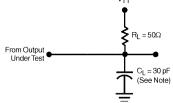
Note 8: For CK, \overline{CK} signals input slew rates are \geq 1 V/ns.

Capacitance (Note 9)

Symbol	Parameter	Min	Тур	Max	Units	Conditions
C _{IN}	Data Pin Input Capacitance	2.0		3.0	pF	$V_{DD} = 2.5V, V_{I} = V_{REF} \pm 350 \text{ mV}$
	CK, CK - Input Capacitance	2.5		3.5	pF	$V_{DD} = 2.5V, V_{ICR} = 1.25V, V_{I(PP)} = 360 \text{ mV}$
	RESET	2.5		3.5	pF	$V_{DD} = 2.5V$, $V_I = V_{DD}$ to GND

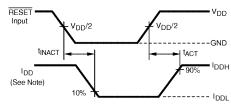
Note 9: T_A = +25°C, f = 1 MHz, Capacitance is characterized but not tested.

AC Loading and Waveforms (See Notes A through F below)



Note: C_L includes probe and jog capacitance

FIGURE 1. AC Test Circuit



Note: I_{DD} tested with clock and data inputs held at V_{DD} or GND, and $I_{O}=0$ mA.

FIGURE 3. Voltage and Current Waveforms Inputs
Active and Inactive Times

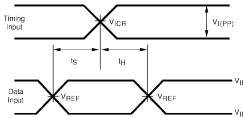
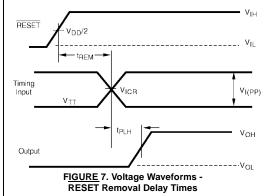


FIGURE 5. Voltage Waveforms - Setup and Hold Times



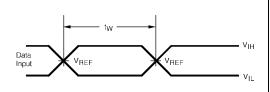


FIGURE 2. Voltage Waveforms - Pulse Duration

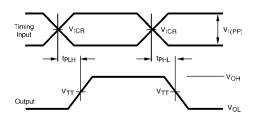


FIGURE 4. Voltage Waveforms - Propagation Delay Times

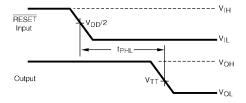


FIGURE 6. Voltage Waveforms - RESET Propagation Delay Times

Note A: All input pulses are supplied by generators having the following characteristics:

PRR \leq 10 MHz, $Z_0=50\Omega,$ input slew rate = 1V/ns \pm 20% (unless otherwise specified).

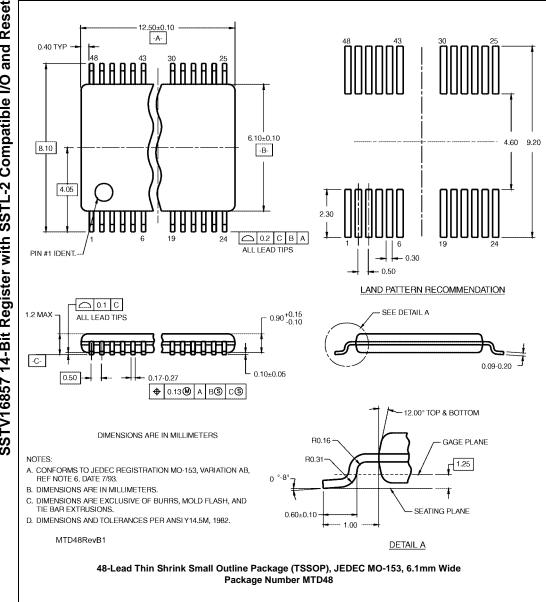
Note B: The outputs are measured one at a time with one transition per measurement.

Note C: $V_{TT} = V_{REF} = V_{DD}/2$.

Note D: $V_{IH} = V_{REF}$ +310 mV (AC voltage levels) for differential inputs. $V_{IH} = V_{DD}$ for LVCMOS input.

Note E: $V_{IL} = V_{REF}$ –310 mV (AC voltage levels) for differential inputs. V_{IL} = GND for LVCMOS input.

Note F: Removal time (t_{REM}) is tested with one data input held active HIGH. The propagation time from CK to the corresponding output must meet valid timing specifications for the measurement to be accurate.



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